International Rectifier

HEXFET® Power MOSFET

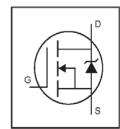
- · Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- · Lead-Free

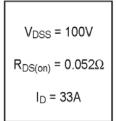
Description

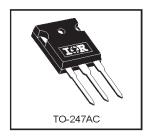
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

IRFP140NPbF







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10VS	33	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10VS	23	A
I _{DM}	Pulsed Drain Current ①⑤	110	
P _D @T _C = 25°C	Power Dissipation	140	W
	Linear Derating Factor	0.91	W/°C
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS}	Single Pulse Avalanche Energy ②⑤	300	mJ
I _{AR}	Avalanche Current ①	16	Α
E _{AR}	Repetitive Avalanche Energy①	14	mJ
d∨/dt	Peak Diode Recovery dv/dt ③⑤	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	1
	Mounting torque, 6-32 or M3 screw.	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
R ₀ JC	Junction-to-Case			1.1	
R _{ecs}	Case-to-Sink, Flat, Greased Surface		0.24		°C/W
R _{θJA}	Junction-to-Ambient			40	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			٧	$V_{GS} = 0V$, $I_D = 250 \mu A$
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I _D = 1mA⑤
R _{DS(on)}	Static Drain-to-Source On-Resistance	_		0.052	Ω	V _{GS} = 10V, I _D = 16A ⊕
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
g fs	Forward Transconductance	11			S	V _{DS} = 50V, I _D = 16A ^⑤
1	Drain-to-Source Leakage Current			25	μA	V _{DS} = 100V, V _{GS} = 0V
i loss	Diani-to-Source Leakage Current			250	μA	$V_{DS} = 80V$, $V_{GS} = 0V$, $T_{J} = 150$ °C
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
l _{GSS}	Gate-to-Source Reverse Leakage			-100	117	V _{GS} = -20V
Qg	Total Gate Charge			94		I _D = 16A
Q _{gs}	Gate-to-Source Charge			15	nC	V _{DS} = 80V
Q _{gd}	Gate-to-Drain ("Miller") Charge			43		V _{GS} = 10V, See Fig. 6 and 13 ⊕⑤
t _{d(on)}	Turn-On Delay Time		8.2			V _{DD} = 50V
tr	Rise Time		39			I _D = 16A
t _{d(off)}	Turn-Off Delay Time		44		ns	$R_G = 5.1\Omega$
t _f	Fall Time		33			$R_D = 3.0\Omega$, See Fig. 10 \oplus $\$$
L	Internal Drain Inductance		E 0			Between lead,
-0	memai Brain madetanee	Inductance — 5.0 —			n⊔	6mm (0.25in.)
ļ_	Internal Course Industrian		nΗ	from package		
L _S	Internal Source Inductance	ctance				and center of die contact
C _{iss}	Input Capacitance		1400			V _{GS} = 0V
Coss	Output Capacitance		330		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		170			f = 1.0MHz, See Fig. 5©

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions		
Is	Continuous Source Current			33		MOSFET symbol		
	(Body Diode)		_	33	Α	showing the		
I _{SM}	Pulsed Source Current			110	1	integral reverse		
	(Body Diode) ①③		_ i _ i		1	110		p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 16A, V _{GS} = 0V ⊕		
trr	Reverse Recovery Time	_	170	250	ns	T,J = 25°C, I _F = 16A		
Qrr	Reverse RecoveryCharge		1.1	1.6	μC	di/dt = 100A/µs ⊕⑤		

Notes:

- ${@}$ Repetitive rating; pulse width limited by max, junction temperature. (See fig. 11)
- \bigcirc V_{DD} = 25V, starting T_J = 25°C, L = 2.0mH R_G = 25 Ω , I_{AS} = 16A. (See Figure 12)
- $\label{eq:loss_def} \begin{tabular}{ll} \begin{tabular}{ll} $I_{SD} \leq 16A, \ di/dt \leq 210A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \\ $T_{J} \leq 175 \mbox{°C} \end{tabular}$
- 1 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- © Uses IRF540N data and test conditions.

International TOR Rectifier

IRFP140NPbF

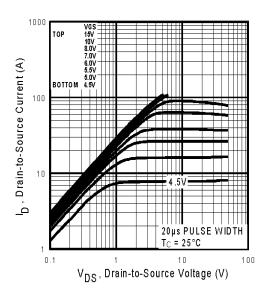


Fig 1. Typical Output Characteristics

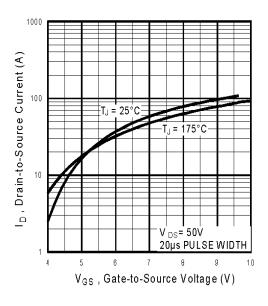


Fig 3. Typical Transfer Characteristics

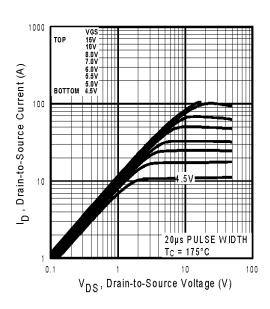


Fig 2. Typical Output Characteristics

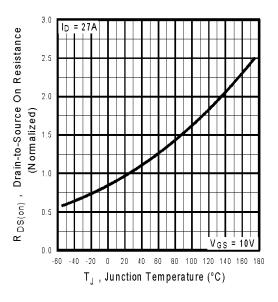


Fig 4. Normalized On-Resistance Vs. Temperature

3

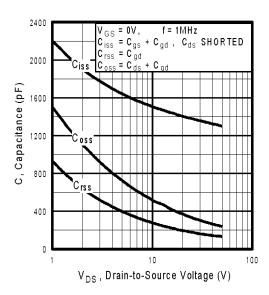


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

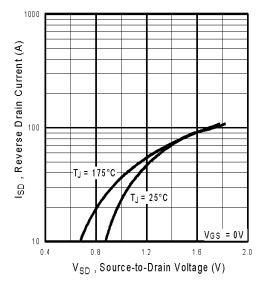


Fig 7. Typical Source-Drain Diode Forward Voltage

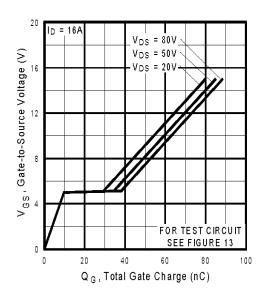


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

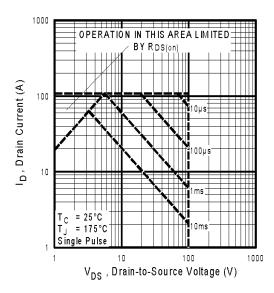


Fig 8. Maximum Safe Operating Area

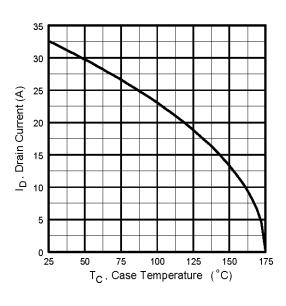


Fig 9. Maximum Drain Current Vs. Case Temperature

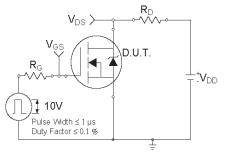


Fig 10a. Switching Time Test Circuit

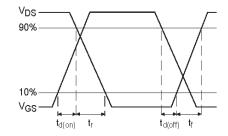


Fig 10b. Switching Time Waveforms

5

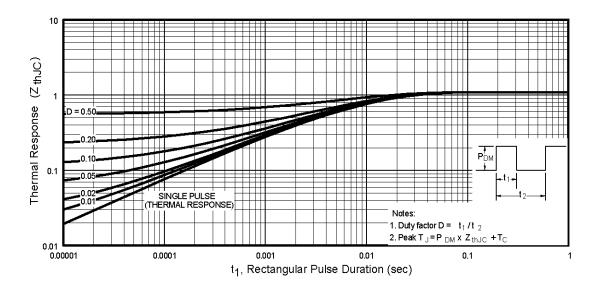


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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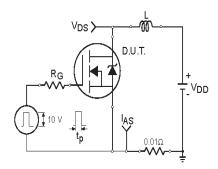


Fig 12a. Unclamped Inductive Test Circuit

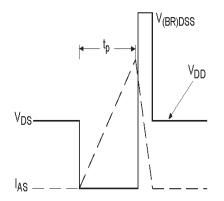


Fig 12b. Unclamped Inductive Waveforms

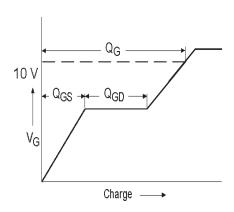


Fig 13a. Basic Gate Charge Waveform 6

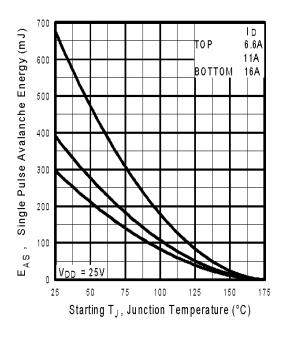


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

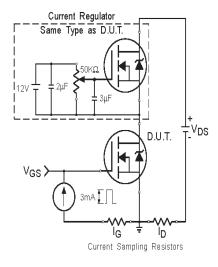
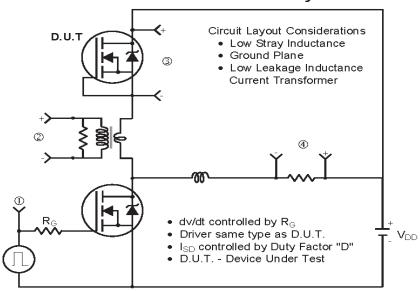
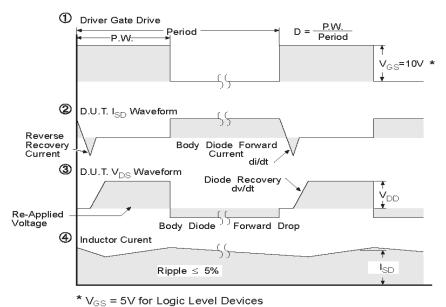


Fig 13b. Gate Charge Test Circuit www.irf.com

Peak Diode Recovery dv/dt Test Circuit



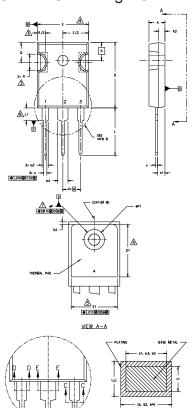


VGS = 5 V IOI LOGIC Level Devices

Fig 14. For N-Channel HEXFETS

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TO-247AC Package Outline Dimensions are shown in millimeters (inches)

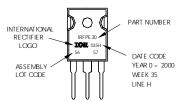


1.	DIMENSIONING	AND TOLE	ERANCING PI	R ASME Y	14,5M 199	94.
2.	DIMENSIONS	ARE SHOWN	IN INCHES	[MILLIMETE	ERS]	
<u> </u>	CONTOUR OF	SLOT OPT	IONAL.			
^	DIMENSION D	& F DO N	IOT INCLUDE	MOID FLA	SH MOLE	FLASH SHALL NOT EXCEED .005" (0.127)
						OUTERMOST EXTREMES OF THE PLASTIC BODY.
<u> </u>	THERMAL PA	D CONTOUR	OPTIONAL	WITHIN DIM	ENISONS	D1 & E1,
<u>6</u> .	LEAD FINISH	LINCONTRO	LIED IN LE			
_				0.5 05 1		E TOP OF THE PART WITH A MAXIMUM HOLE
	DIAMETER OF			IGLE OF I.	5 10 16	IE TOP OF THE PART WITH A MAXIMUM HOLE
			•	INE TO-2	17 WITH T	THE EXCEPTION OF DIMENSION C.
u.	OUTLINE CON	i OKM3 TO	SEDEC GOTE		**	THE EXCELLIPTION OF DIMENSION C.
		DIME	NSIONS			
SYMBO	L INC	HES	MILLIM	ETERS		
	MIN.	MAX.	MIN.	MAX.	NOTES	
A	.183	.209	4.65	5.31		LEAD ASSIGNMENTS
A1	.087	.102	2.21	2.59		
A2	.059	.098	1.50	2.49		HEXFET
b	.039	.055	0.99	1.40		
ь1	.039	.053	0.99	1,35		1,- GATE
ь2	.065	.094	1.65	2.39		2 DRAIN
b3	.065	.092	1.65	2.37		3 SOURCE
b4	.102	.135	2.59	3.43		4,- DRAIN
b5	.102	.133	2.59	3.38		
C	.015	.034	0.38	0.86		
c1	.015	.030	0.38	0.76		IGBTs, CoPACK
D	.776	.815	19.71	20.70	4	1 GATE
D1	.515	-	13.08	-	5	2 COLLECTOR
D2	.020	.030	0,51	0,76		3 EMITTER
E	.602	.625	15.29	15,87	4	4 COLLECTOR
E1	.540		15,72	-]	i, oceaeoron
е		BSC		BSC	1 1	
øk		10		54	1	DIODES
L	.559	.634	14.20	16.10		
L1	.146	,169	3.71	4.29		1 ANODE/OPEN
N		3		BSC	4	2 CATHODE
øΡ	.140	,144	3.56	3.66		3 ANODE
øP1	1 -	.275	II -	6.98		
Q	.209	.224	5.31	5.69		
R S	.178	.216	4.52	5.49	4	
		BSC	11 5.51	BSC	1 1	

TO-247AC Part Marking Information

SECTION C-C, D-D, E-E





Data and specifications subject to change without notice.

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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/